

Special Issue

Digital Image Security and Privacy Protection

Message from the Guest Editor

Fast advancements in communication technologies increased the number of transmitted digital images. Images are used in many applications, including medical images, remote sensing, social networks, military purposes, etc. Image content protection and preserving intellectual rights are challenging problems. Copyright protection of digital images is a vital security issue. Watermarking technology of digital images has been extensively studied and used as a powerful copyright protection technology and in the authentication of the content of digital images and software protection. In addition, based on the images' importance, it is necessary to ensure their authenticity and keep their contents tamper-proof. We invite scientists and researchers to submit papers for this important Special Issue entitled "Digital Image Security and Privacy Protection". In this Special Issue, original research articles and reviews are welcome. Potential topics include, but are not limited to, the following:

- Image encryption;
- Image watermarking;
- Image forgery detection;
- Image copyright protection;
- Image authentication;
- Image information hiding.

Guest Editor

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Deadline for manuscript submissions

closed (31 January 2024)



Applied Sciences

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CiteScore 5.5



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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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